

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Bruno GHYSELEN *et al.*

Application No.:

Group Art Unit:

Filing Date: Concurrently herewith

Examiner:

For: TRANSFER OF A THIN LAYER FROM A
WAFER COMPRISING A BUFFER LAYER

Attorney Docket No.: 4717-7600

INFORMATION DISCLOSURE STATEMENT

MS PATENT APPLICATION

Commissioner for Patents
Washington, D.C. 20231

Sir:

Pursuant to Applicant's duty of disclosure under 37 C.F.R. § 1.56, enclosed are copies of twelve (12) references listed on the enclosed Form PTO-1449 for the Examiner's review. Also enclosed is a copy of the International Search Report from the French priority application on which some of the references were cited. It is respectfully requested that the references be made of record in this application by the Examiner's completion and return of the attached Form PTO-1449.

No fee is believed to be due for the submission of these references. Should any fees be required, however, please charge such fees to Winston & Strawn Deposit Account No. 501-814.

Respectfully submitted,

Date

July 8, 2003



E. Bradley Gould (Reg. No. 41,792)
For: Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN
Customer No. 28765

202-371-5771

LIST OF REFERENCES CITED BY APPLICANT Form PTO-1449 (Use several sheets if necessary)					ATTY. DOCKET NO.: 4717-7600		APPLICATION NO.:	
					APPLICANT: Bruno GHYSELEN et al.			
Sheet 1 of 1					FILING DATE: Concurrently herewith		GROUP:	
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	A	6,573,126	06/2003	Cheng <i>et al.</i>	438	149		
	B	6,524,935	02/2003	Canaperi <i>et al.</i>	438	478		
	C	6,410,371	06/2002	Yu <i>et al.</i>	438	151		
	D	6,403,450	06/2002	Maleville <i>et al.</i>	438	471		
	E	6,323,108	11/2001	Kub <i>et al.</i>	438	458		
	F	6,059,895	05/2000	Chu <i>et al.</i>	148	33.1		
	G	5,882,987	03/1999	Srikrishnan	438	458		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	H	02/33746	04/2002	WO				
	I	2 365 214	02/2002	Great Britain				
	J	01/99169	12/2001	WO				
	K	01/11930	02/2001	WO				
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
	L	L.J. Huang <i>et al.</i> , <i>SiGe-On-Insulator Prepared by Wafer Bonding and Layer Transfer for High Performance Field-Effect Transistors</i> , Applied Physics Letters, February 26, 2002, Vol 78, No. 9						
EXAMINER					DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								